Tech Info Library

Apple IIe: Component diagnostics (2 of 2)

Revised: 7/2/87
Security: Everyone

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ROMs E8 and E10 are tested individually. Since the processor will hang as soon as a failure is detected, and if the failure is in ROM 8, the subsequent test of E10 won't be made. Its possible that if E8 is bad, the diagnostics won't run at all, since they're located in the E8 ROM.

ROM:E8	The ROM at location E8 failed the checksum test.
ROM:E10	The ROM at location E10 failed the checksum test.

The RAM test is a two pass, up and down, write then read test. Any failure is logged and then decoded to provide you with the location of the failed chip.

RAM:F6	A failure detected in the RAM at location F6.
F7	A failure detected in the RAM at location F7.
F8	A failure detected in the RAM at location F8.
F9	A failure detected in the RAM at location F9.
F10	A failure detected in the RAM at location F10.
F11	A failure detected in the RAM at location F11.
F12	A failure detected in the RAM at location F12.
F13	A failure detected in the RAM at location F13.

"KERNEL OK" will appear on the screen when the Apple IIe passes.

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